Hybrid 5p76 Traveler

April 17, 2000

1 Connectivity

Repairs on shorts:
Fixes for opens:

2 Chips

The following chips were assembled on this hybrid (in the order that the chips get read out):
Hybrid 5P76 has die: 217-068 217-069 217-070 217-071 217-076

3 Data Analysis Summary

The following summarizes the findings of the Burn-in data analysis program. The first chip in the readout name is numbered 0.

```
% Hybrid 5p76 classification info. Created 15:11:22 01/13/00

Hybrid 5p76 quality: fair
Chip classification: fair good fair fair good
Bad channels (chip-channel): 0-98 2-13 2-103 3-85
Bad cells: none
Random bad capacitors (chip-cell-channel): 2-0-9 2-11-9 2-14-9
   2-15-9 2-16-9 2-21-9 2-23-9 2-25-1 2-25-9 2-28-9 2-29-9
   2-34-9 2-37-9 2-38-9 2-39-9 2-4-9 2-5-9 2-7-9 2-8-9
Channels at pedestal needed for DCMS: 31.7 31.7 33.5 34.4 32.7
```

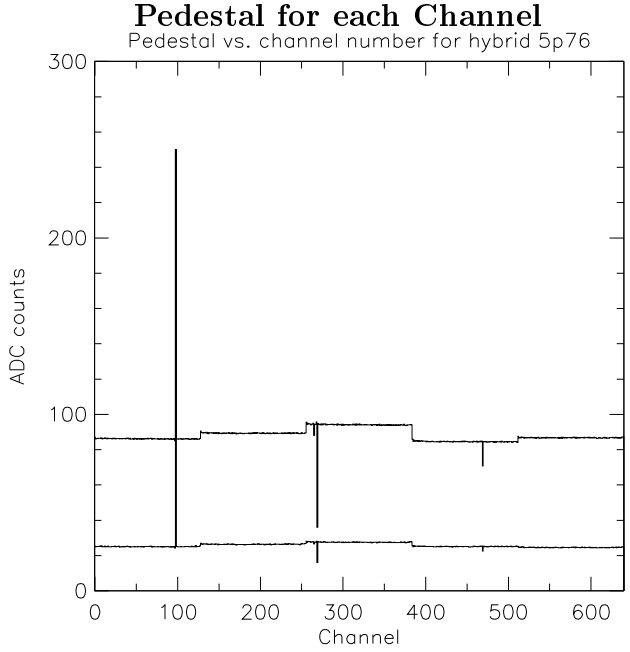
4 Comments

Encapsulated. FE DV finger gold bonds. HV tested.

5 Pedestal

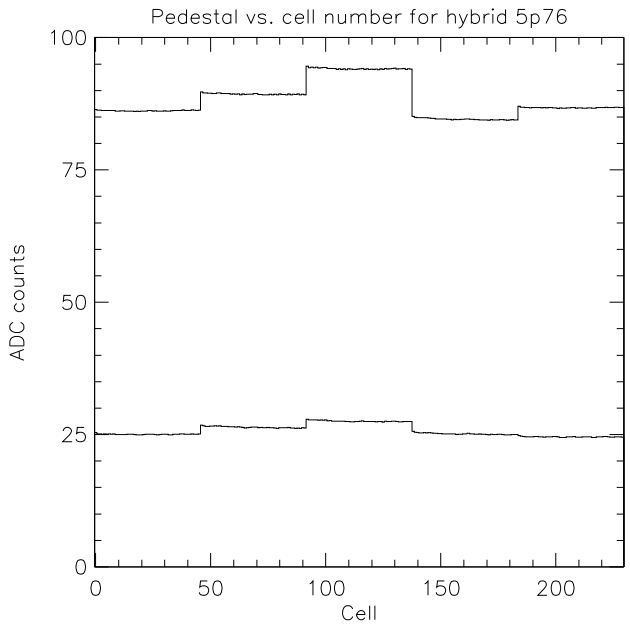
The following plot shows the pedestals vs. channel number with and without charge injection:

Pedestal for each Channel



The following plot shows the average pedestal vs. pipeline cell ID with and without charge injection. The x-axis is cell ID offset by 46 for each chip. Thus cell ID 5 for chip 1 is at x=5, chip 2 at x=51, chip 3 at x=97, etc.

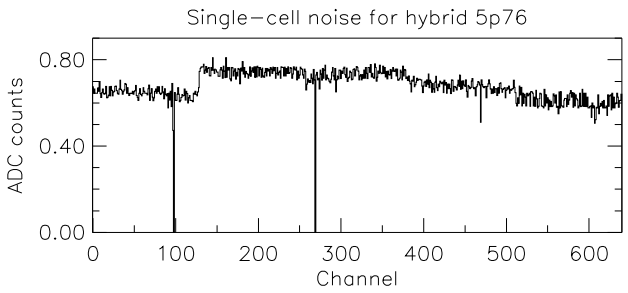
Pedestal vs. Pipeline Cell ID

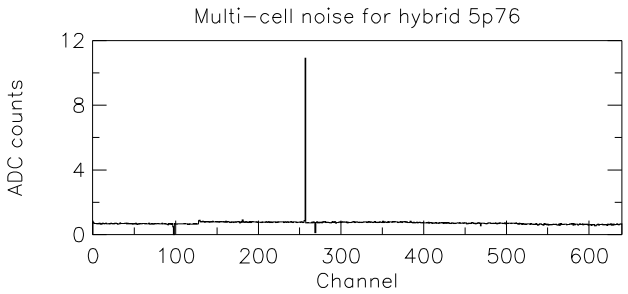


6 Noise

The following plots show the single-cell and multi-cell RMS noise:

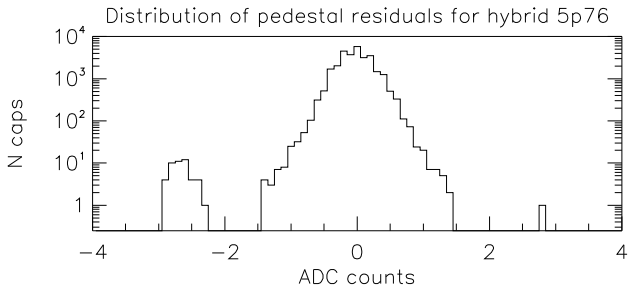
RMS Noise

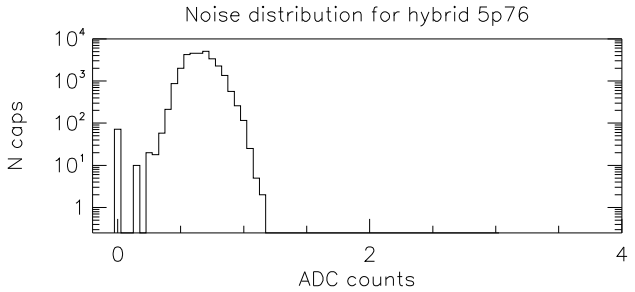




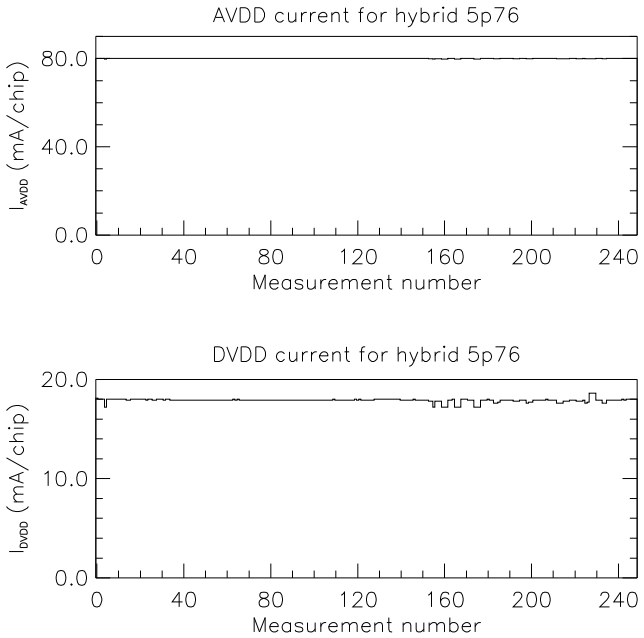
The following are histograms of the pedestal of each pipeline capacitor relative to the chip average (top); and the RMS noise of each capacitor (bottom):

Distribution of Pedestals and Noise





7 Currents

The following plots show the supply currents per chip as a function of measurment number. Currents are measured approximately every 10 minutes:

Supply Currents During Burn-in